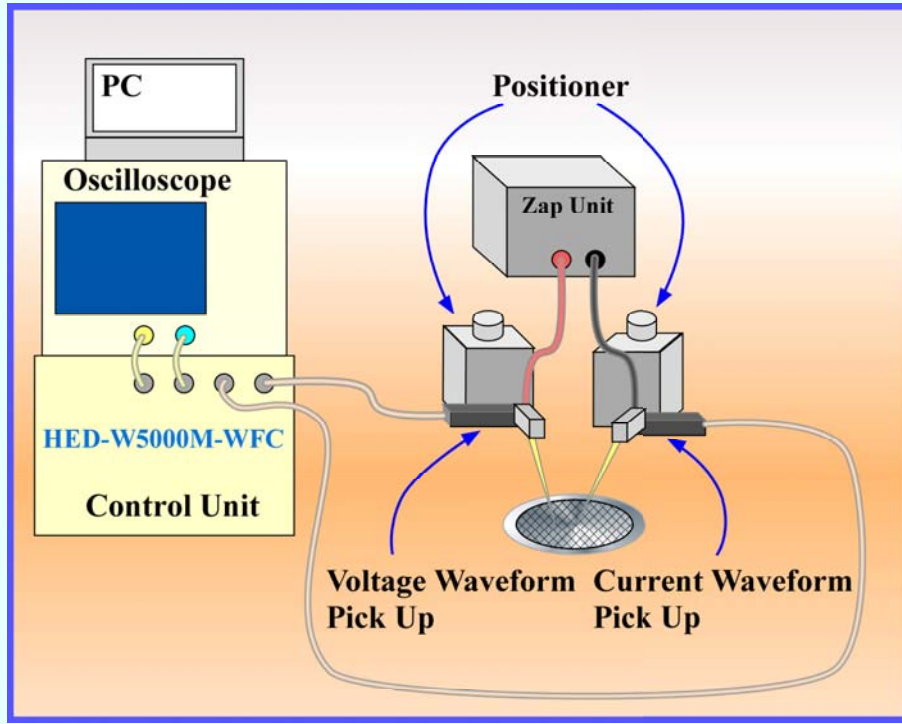


Real-time waveform capture

Real-time waveform capture ESD Tester

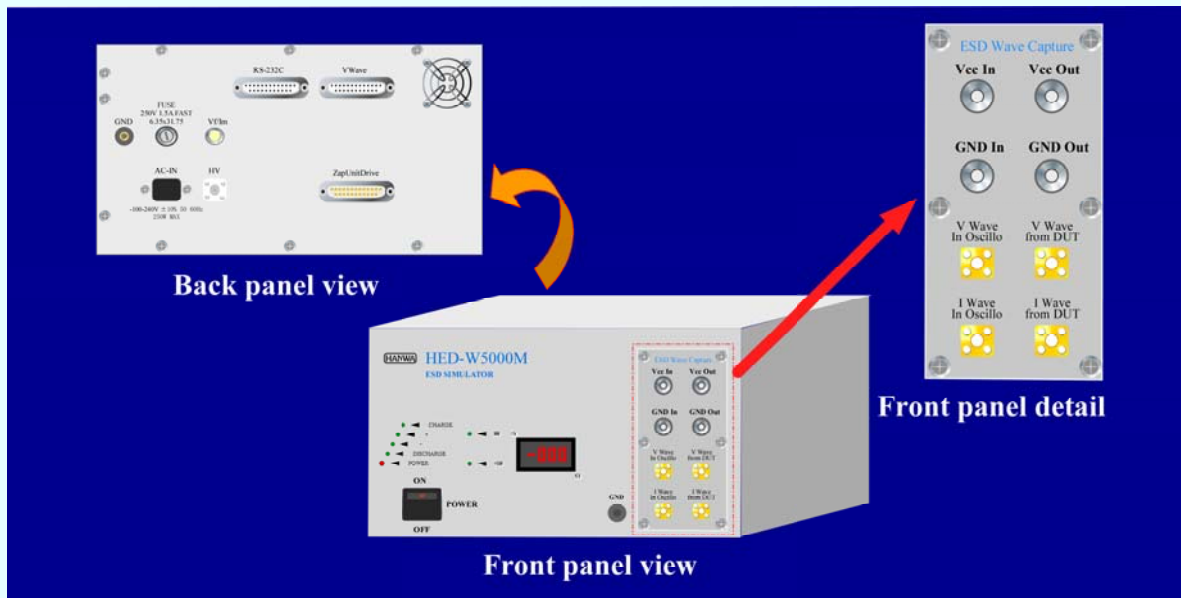
HED-W5000M-WFC



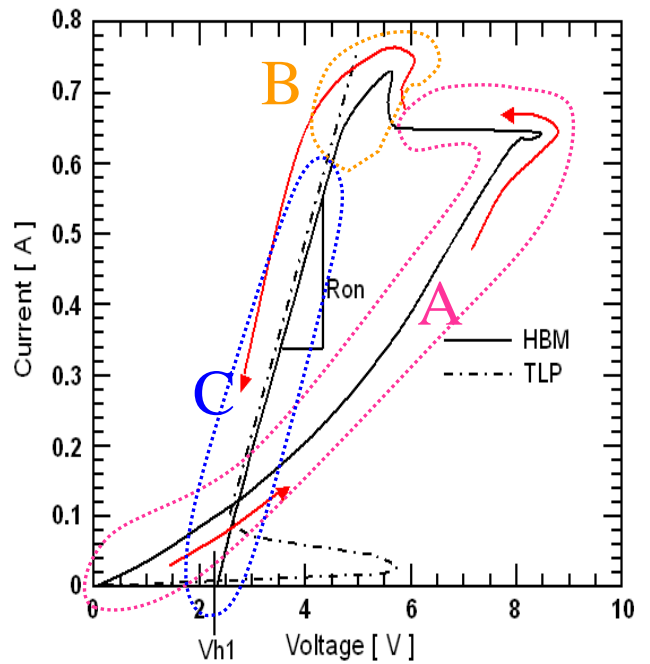
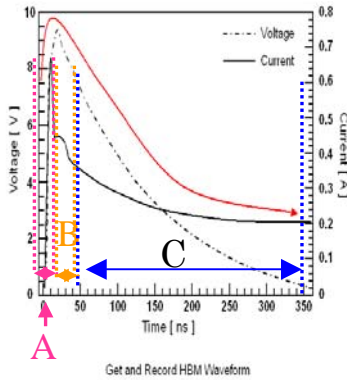
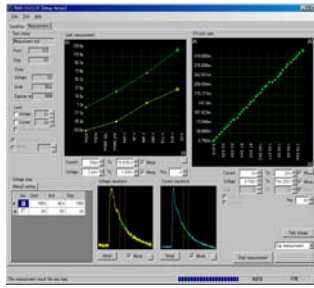
US Patent pending

Features

1. Real-time waveform capture HBM test on Wafer level.
2. Performs HBM/MM zap (Complies with JEDEC/ESDA/JEITA).
3. Connects with two outputs to any device such as wafers.
4. Zap unit can be installed on the customer's PROBER.
5. Clear correlation of the test results of a package device.



Software & Theory



HBM Waveform analysis (Compare TLP and HBM I/V Curves)

Specification

Model	HED-W5000M-WFC		
Waveform	HBM	JEDEC EIA/JESD22-A114-B, ESDASTM5.1-1998, MIL-STD883E	
	MM	JEDEC EIA/JESD22-A115-A, ESDASTM5.2-1999,	
Charging voltage	0 ~ +/-4kV (8kV option)		
Charging resolution	10V		
Charging accuracy	1 % +/-10V		
ZAP count	1 ~ 9		
Interval time	0.8 ~ 9.9 S		
Test pins	Manual positioning		
X-Y-Z Move range & resolution	Depend on Customer's Manipulator		
Physical (main unit)	330(W) / 520(D) / 200(H)	15 Kg	(PC no contained)
Physical (Zap unit)	75(W) / 120(D) / 105(H)	1 Kg	
Curve Tracing voltage & step & Resolution	0 ~ +/- 40V	0.1V step	0.1V Resolution
Curve Tracing current	Max 100mA		
Detection resistance	100,1k,10k,100k ohm		
Measurement range	100nA, 1uA, 10uA, 100uA, 1mA, 10mA, 100mA		
Curve Tracing Accuracy	1% of range		
Measurement point	max 20 point		
Judgment	Variable quantity, absolute quantity		
Main unit control	RS-232C		
Oscilloscope model	Tektronix TDS3052B		
Oscilloscope control	GPIB		
Operation	Windows XP		

HANWA HANWA ELECTRONIC IND.CO.LTD
Headquarters: 689-3,Ogaito, Wakayama Pref.649-6272, Japan
 TEL:+81-73-477-4435 FAX:+81-73-477-3445
Kumamoto Plant: TEL:+81-968-34-3339 FAX:+81-968-34-3369
Tokyo Office: TEL:+81-3-5767-5677 FAX:+81-3-5767-5688
<http://www.hanwa-ei.co.jp/> info@hanwa-ei.co.jp

● Agent

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